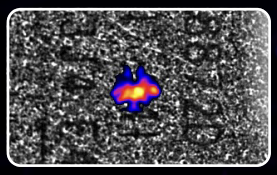
Universal electrical localization

From boards to 3D stacks, the Thermo Scientific™ ELITE™ System enhanced with RF-LIT enables comprehensive electrical defect coverage and supports true open detection.

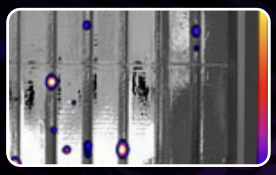
Complete electrical defect detection

Hard shorts



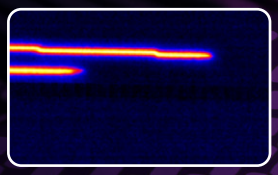
Direct electrical short circuits detected via thermal emission.

Leakage paths



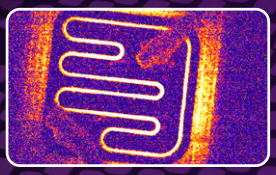
Low-resistance paths rapidly localized via strong thermal signatures.

Resistive opens



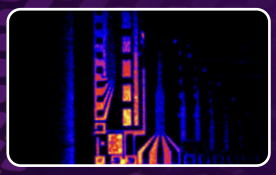
Partial interruptions in metal lines or vias identified.

High-resistance leakage



Paths localized via subtle thermal signatures stimulated by RF-LIT.

True opens



Detectable heat signatures of open traces stimulated by RF LIT

Why RF-LIT matters

Traditional LIT:

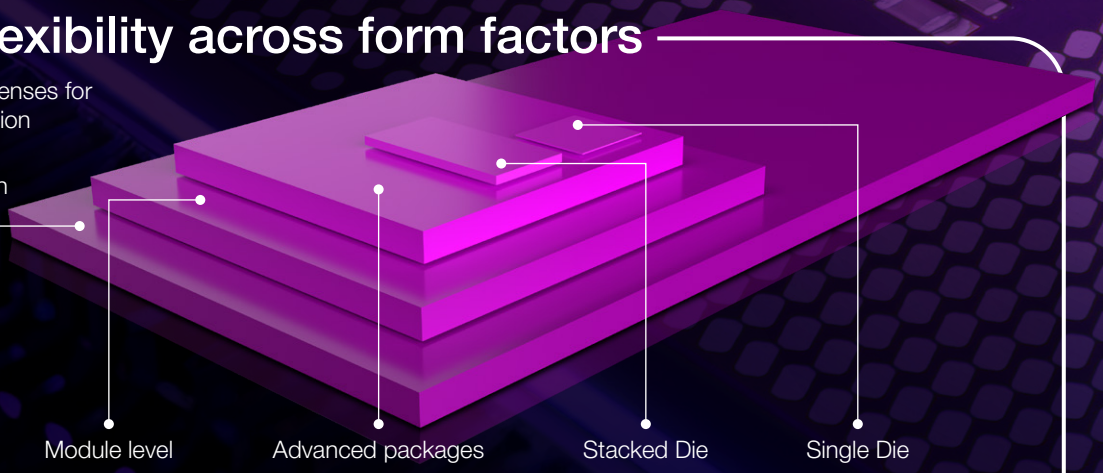
- Requires electrical current
- Detects shorts and leakage

RF-LIT:

- Generates heating in open paths
- Detects faults with subtle or no current signal

Ultimate flexibility across form factors

- Large field-of-view lenses for board-level localization
- High resolution for device-level isolation in 3D



Key advantages of the ELITE System

- Detects shorts, leakage, resistive opens, and true opens
- Non-destructive technique
- Works across multiple device technologies
- Reduces open failure debug time from hours to minutes

One platform – All electrical failures – Maximum insight

Learn more at **thermofisher.com/elite**